



PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application No.: 10/759,267
Filing Date: January 20, 2004
Applicant: Geum-jin Yum
Group Art Unit: 2829
Examiner: Paresh H. Patel

Title: **INTEGRATED MONITORING BURN-IN TEST METHOD FOR
MULTI-CHIP PACKAGE**

Attorney Docket: 2557-000206/US

Customer Service Window
Randolph Building
401 Dulany Street
Alexandria, VA 22314
Mail Stop Amendment AF

January 11, 2007

AMENDMENT AFTER FINAL

Sir:

In response to the Final Office Action mailed November 1, 2006, the following amendment and remarks are respectfully submitted in connection with the above-identified application.

Amendments to the Claims begin on page 2 of this paper.

Remarks begin on page 9 of this paper.

	Claims remaining after Amendment		Highest number previously paid for		Present extra
Total	26	-	26	=	0
Independent	4	-	4	=	0